



P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY			
V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (A)	Q_g (Typ)
-30	0.046 @ $V_{GS} = -4.5$ V	-6.3	17
	0.065 @ $V_{GS} = -2.5$ V	-5.3	

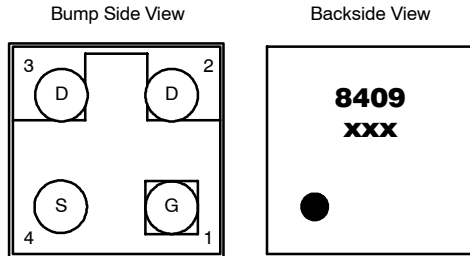
FEATURES

- TrenchFET® Power MOSFET
- New MICRO FOOT® Chipscale Packaging
Reduces Footprint Area, Profile (0.62 mm) and
On-Resistance Per Footprint Area
- Pin Compatible to Si8401DB

APPLICATIONS

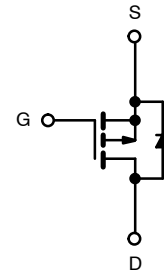
- Load Switch, Battery Switch, and PA Switch for
Portable Devices

MICRO FOOT



Device Marking: 8409
xxx = Date/Lot Traceability Code

Ordering Information: Si8409DB-T1—E1



P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter		Symbol	5 secs	Steady State	Unit
Drain-Source Voltage		V _{DS}	−30		V
Gate-Source Voltage		V _{GS}	± 12		
Continuous Drain Current (T _J = 150°C) ^a	T _A = 25°C	I _D	−6.3	−4.6	A
	T _A = 70°C		−5.1	−3.7	
Pulsed Drain Current		I _{DM}	−25		
continuous Source Current (Diode Conduction) ^a		I _S	−2.5	−1.3	
Maximum Power Dissipation ^a	T _A = 25°C	P _D	2.77	1.47	W
	T _A = 70°C		1.77	0.94	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	−55 to 150		°C
Package Reflow Conditions ^b	VPR		215		
	IR/Convection		220		

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^a	$t \leq 5$ sec	R_{thJA}	35	45	$^\circ\text{C/W}$
	Steady State		72	85	
Maximum Junction-to-Foot (drain)	Steady State	R_{thJF}	16	20	

Notes

- a. Surface Mounted on 1" x 1" FR4 Board.
b. Refer to IPC/JEDEC (J-STD-020A), no manual or hand soldering.

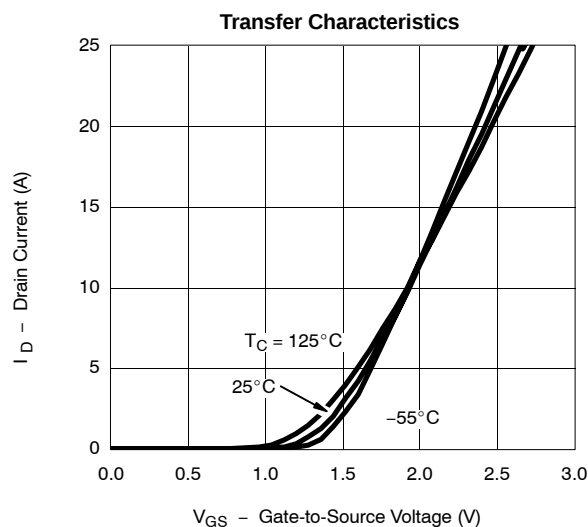
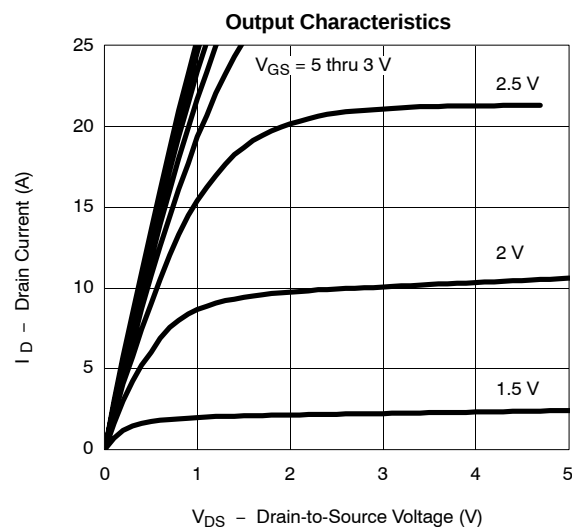
SPECIFICATIONS ($T_J = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

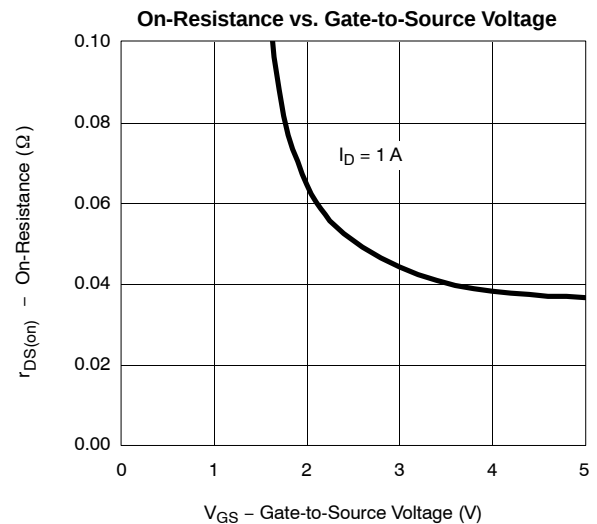
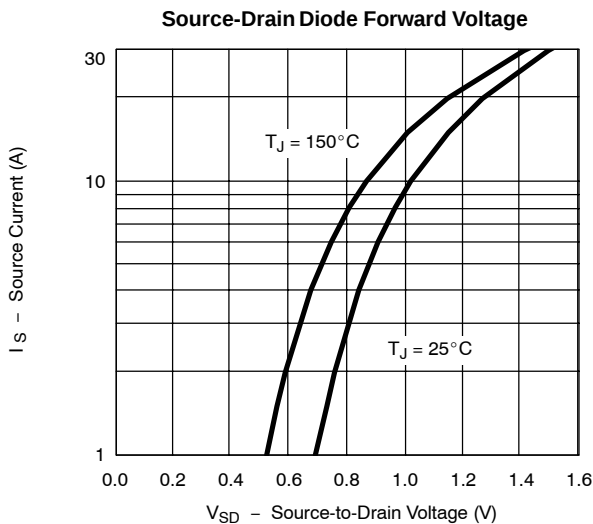
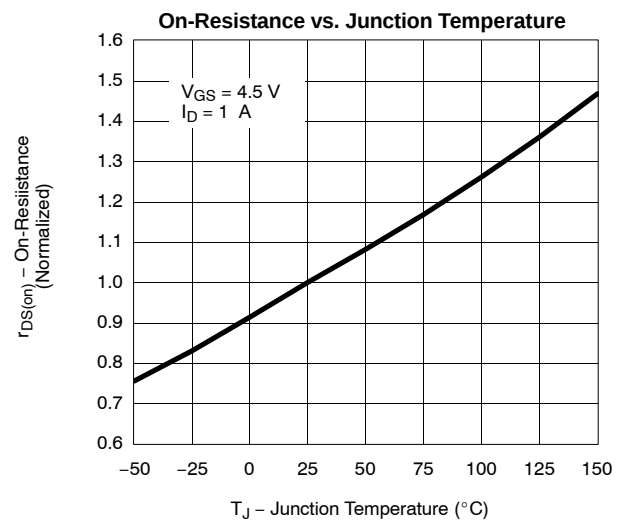
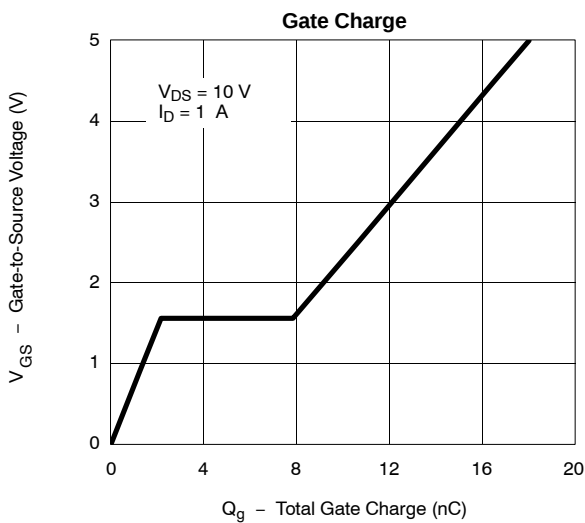
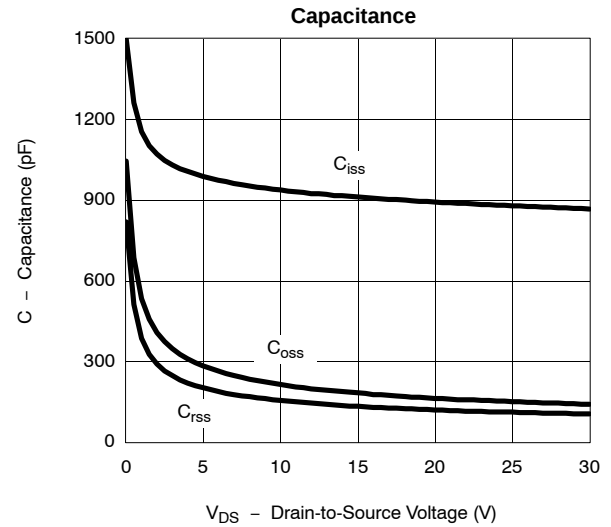
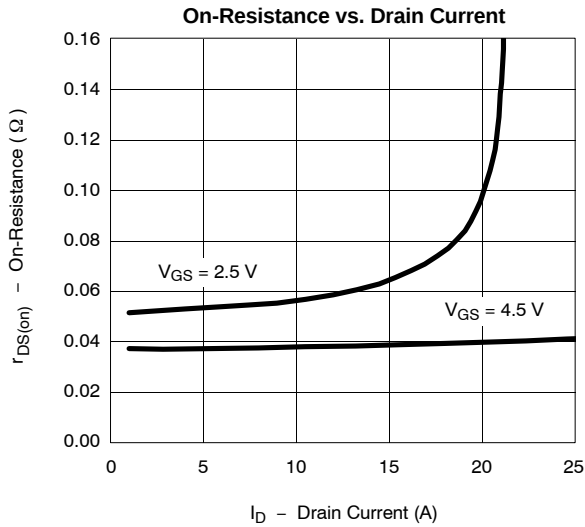
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = -250\ \mu\text{A}$	-0.6		-1.4	V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\ \text{V}$, $V_{GS} = \pm 12\ \text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -30\ \text{V}$, $V_{GS} = 0\ \text{V}$			-1	μA
		$V_{DS} = -30\ \text{V}$, $V_{GS} = 0\ \text{V}$, $T_J = 70^\circ\text{C}$			-5	
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \leq -5\ \text{V}$, $V_{GS} = -4.5\ \text{V}$	-5			A
Drain-Source On-State Resistance ^a	$r_{DS(on)}$	$V_{GS} = -4.5\ \text{V}$, $I_D = -1\ \text{A}$		0.038	0.046	Ω
		$V_{GS} = -2.5\ \text{V}$, $I_D = -1\ \text{A}$		0.052	0.065	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -10\ \text{V}$, $I_D = -1\ \text{A}$		6.4		S
Diode Forward Voltage ^a	V_{SD}	$I_S = -1\ \text{A}$, $V_{GS} = 0\ \text{V}$		-0.8	-1.1	V
Dynamic^b						
Total Gate Charge	Q_g	$V_{DS} = -10\ \text{V}$, $V_{GS} = -4.5\ \text{V}$, $I_D = -1\ \text{A}$		17	26	nC
Gate-Source Charge	Q_{gs}			2.2		
Gate-Drain Charge	Q_{gd}			5.7		
Gate Resistance	R_g	$f = 1\ \text{MHz}$		22		Ω
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -10\ \text{V}$, $R_L = 10\ \Omega$ $I_D \cong -1\ \text{A}$, $V_{GEN} = -4.5\ \text{V}$, $R_g = 6\ \Omega$		20	30	ns
Rise Time	t_r			35	55	
Turn-Off Delay Time	$t_{d(off)}$			140	210	
Fall Time	t_f			90	135	
Source-Drain Reverse Recovery Time	t_{rr}	$I_F = -1\ \text{A}$, $di/dt = 100\ \text{A}/\mu\text{s}$		85	130	

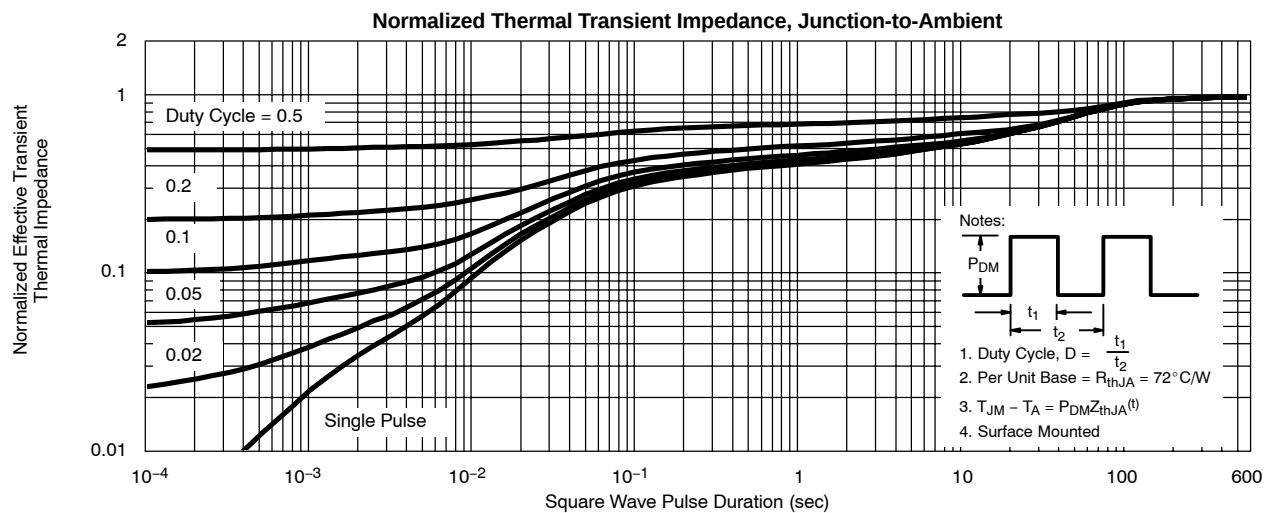
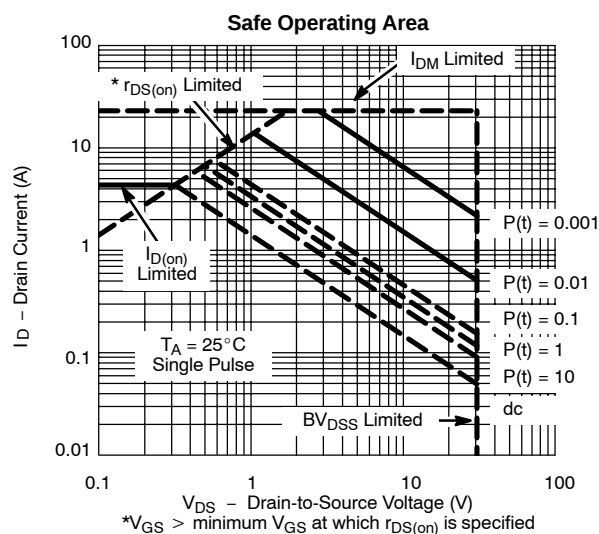
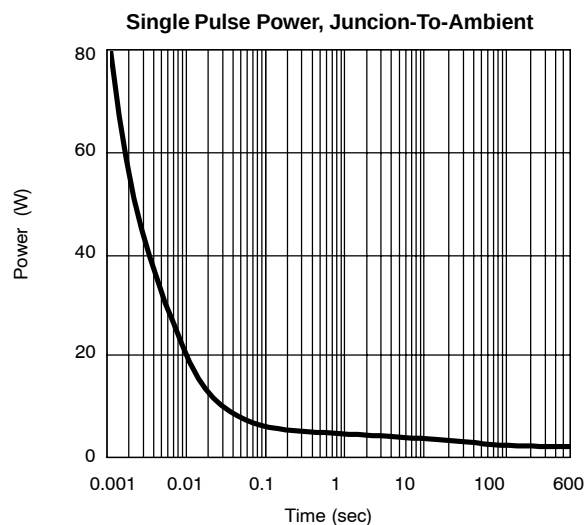
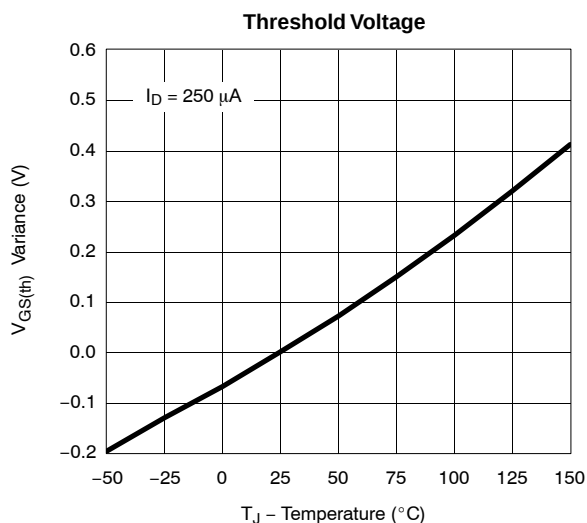
Notes

- a. Pulse test; pulse width $\leq 300\ \mu\text{s}$, duty cycle $\leq 2\%$.
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

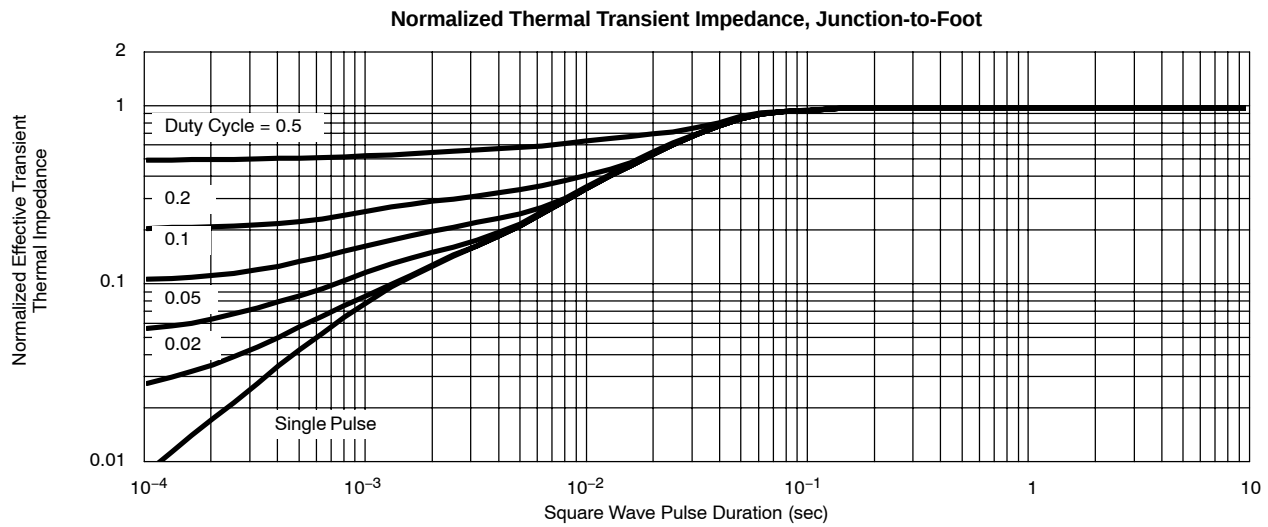
TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

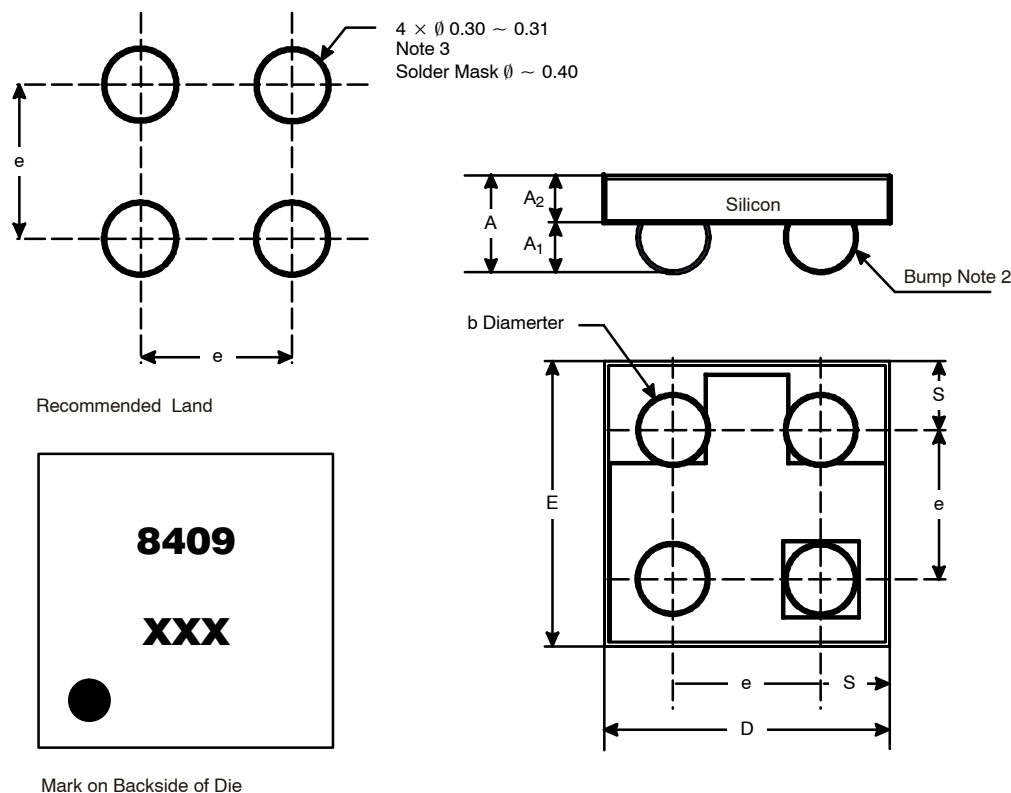
**TYPICAL CHARACTERISTICS (25 °C UNLESS NOTED)**

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PACKAGE OUTLINE
MICRO FOOT: 4-BUMP (2 X 2, 0.8-mm PITCH)

NOTES (Unless Otherwise Specified):

1. Laser mark on the silicon die back, coated with a thin metal.
2. Bumps are lead (Pb)-free.
3. Non-solder mask defined copper landing pad.
4. The flat side of wafers is oriented at the bottom.

Dim	MILLIMETERS*		INCHES	
	Min	Max	Min	Max
A	0.600	0.650	0.0236	0.0256
A ₁	0.260	0.290	0.0102	0.0114
A ₂	0.340	0.360	0.0134	0.0142
b	0.370	0.410	0.0146	0.0161
D	1.520	1.600	0.0598	0.0630
E	1.520	1.600	0.0598	0.0630
e	0.750	0.850	0.0295	0.0335
S	0.370	0.380	0.0146	0.0150

* Use millimeters as the primary measurement.

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